

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices – Mechanical and climatic test methods –
Part 41: Standard reliability testing methods of non-volatile memory devices**

**Dispositifs à semiconducteurs – Méthodes d'essais mécaniques
et climatiques –
Partie 41: Méthodes d'essai normalisées pour la fiabilité des dispositifs
à mémoire non volatile**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –
MECHANICAL AND CLIMATIC TEST METHODS –****Part 41: Standard reliability testing methods
of non-volatile memory devices**

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47/2631/FDIS	47/2643/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

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